

Notice of References Cited		Application/Control No. 09/964,787	Applicant(s)/Patent Under Reexamination ENDOH, TOMOAKI	
		Examiner BENJAMIN O. DULANEY	Art Unit 2625	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,509,074 A	04-1996	Choudhury et al.	713/176
*	B	US-5,720,036 A	02-1998	Garfinkle et al.	709/225
*	C	US-5,987,228 A	11-1999	Nishizawa, Takeshi	358/1.15
*	D	US-6,064,836 A	05-2000	Nakamura et al.	399/8
*	E	US-6,151,464 A	11-2000	Nakamura et al.	399/79
*	F	US-6,378,070 B1	04-2002	Chan et al.	713/155
*	G	US-6,385,728 B1	05-2002	DeBry, Roger K.	726/9
*	H	US-6,667,816 B1	12-2003	Van Buren et al.	358/3.13
*	I	US-6,762,853 B1	07-2004	Takagi et al.	358/1.15
*	J	US-6,859,832 B1	02-2005	Gecht et al.	709/224
*	K	US-7,248,693 B1	07-2007	Tretter et al.	380/55
*	L	US-7,304,753 B1	12-2007	Richter et al.	358/1.15
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.